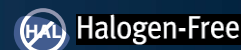


## EPC2207 – Enhancement Mode Power Transistor

 $V_{DS}$ , 200 V $R_{DS(on)}$ , 22 m $\Omega$  $I_D$ , 14 A

Revised July 15, 2022

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Questions:  
Ask a GaN  
Expert



Die Size: 2.8 x 0.9 mm

EPC2207 eGaN® FETs are supplied only in passivated die form with solder bars.

## Applications

- DC-DC converters
- BLDC motor drives
- Sync rectification for AC/DC and DC-DC
- Multi-level AC/DC power supplies
- Wireless power
- Solar micro-inverters
- Robotics
- Class-D audio

## Benefits

- Ultra high efficiency
- No reverse recovery
- Ultra low  $Q_G$
- Small footprint

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



<https://l.ead.me/EPC2207>

## Maximum Ratings

PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	200	V
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ )	14	A
	Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300 \mu\text{s}$ )	54	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature	-40 to 150	

## Thermal Characteristics

PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.4	$^\circ\text{C}/\text{W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	5.1	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	72	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

Static Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 0.2 \text{ mA}$	200			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 160 \text{ V}$		0.05	0.16	mA
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		0.01	1.3	
	Gate-to-Source Forward Leakage <sup>#</sup>	$V_{GS} = 5 \text{ V}$ , $T_J = 125^\circ\text{C}$		0.16	2.9	
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		0.05	0.16	
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 2 \text{ mA}$	0.8	1.1	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 14 \text{ A}$		15	22	m $\Omega$
$V_{SD}$	Source-Drain Forward Voltage <sup>#</sup>	$I_S = 0.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$		1.7		V

<sup>#</sup> Defined by design. Not subject to production test.

Dynamic Characteristics# ( $T_j = 25^\circ\text{C}$  unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_{ISS}$	Input Capacitance	$V_{DS} = 100\text{ V}, V_{GS} = 0\text{ V}$		454	600	pF
$C_{RSS}$	Reverse Transfer Capacitance			0.7		
$C_{OSS}$	Output Capacitance			130	195	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }100\text{ V}, V_{GS} = 0\text{ V}$		186		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			234		
$R_G$	Gate Resistance			0.3		$\Omega$
$Q_G$	Total Gate Charge	$V_{DS} = 100\text{ V}, V_{GS} = 5\text{ V}, I_D = 14\text{ A}$		4.5	5.9	nC
$Q_{GS}$	Gate-to-Source Charge	$V_{DS} = 100\text{ V}, I_D = 14\text{ A}$		1.3		
$Q_{GD}$	Gate-to-Drain Charge			0.7		
$Q_{G(TH)}$	Gate Charge at Threshold			0.8		
$Q_{OSS}$	Output Charge	$V_{DS} = 100\text{ V}, V_{GS} = 0\text{ V}$		23	35	
$Q_{RR}$	Source-Drain Recovery Charge			0		

# Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Figure 1: Typical Output Characteristics at 25°C

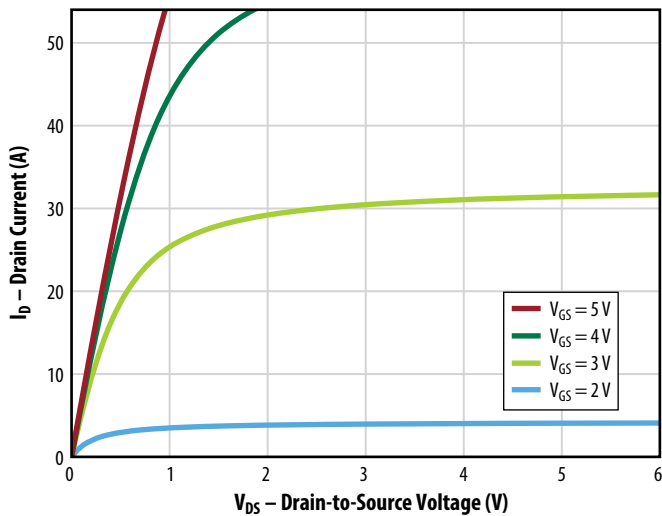


Figure 2: Typical Transfer Characteristics

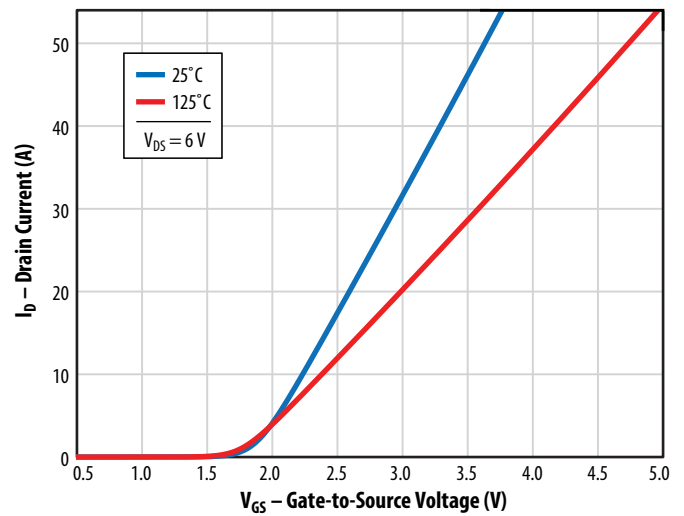


Figure 3: Typical  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain Currents

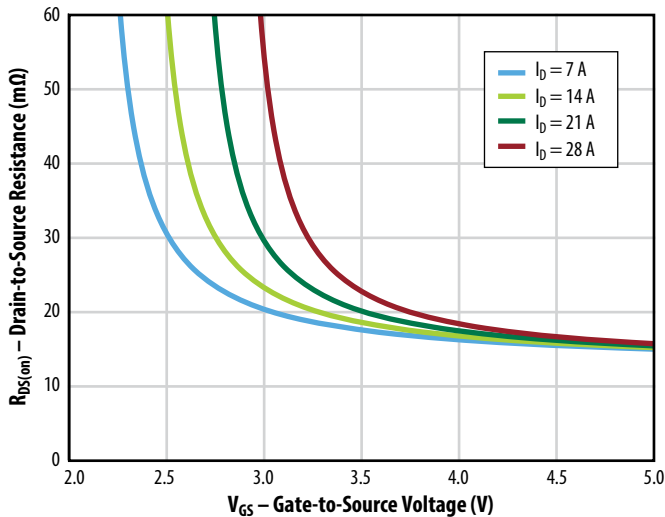


Figure 4: Typical  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures

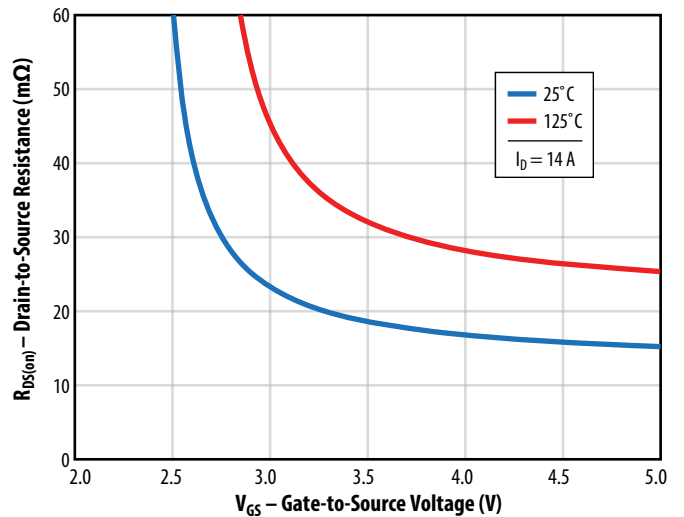


Figure 5a: Typical Capacitance (Linear Scale)

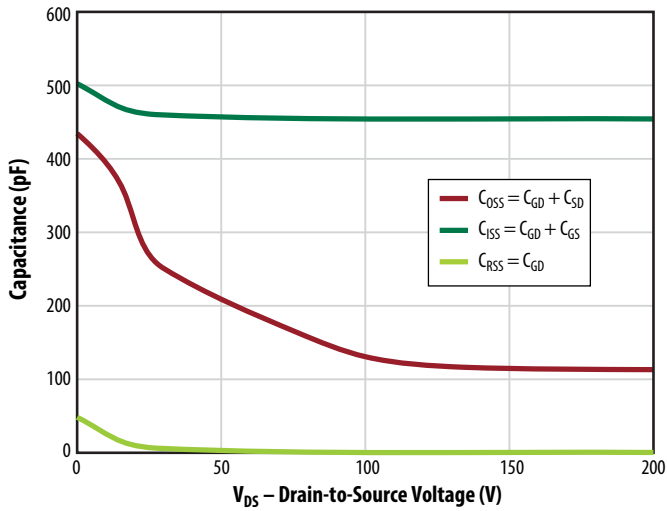


Figure 5b: Typical Capacitance (Log Scale)

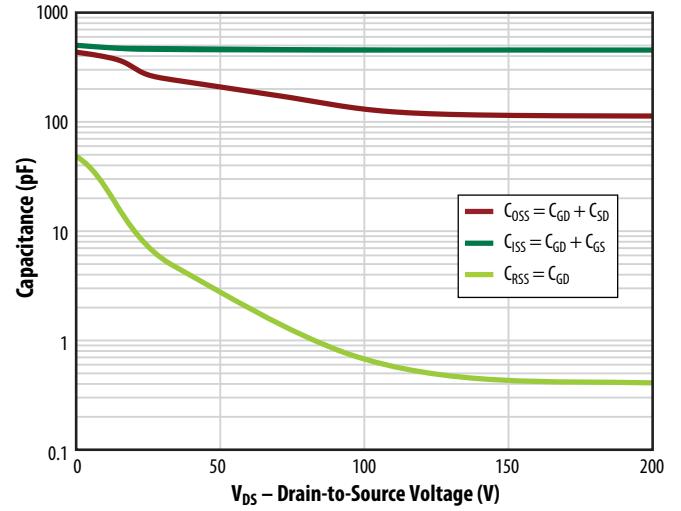


Figure 6: Typical Output Charge and  $C_{OSS}$  Stored Energy

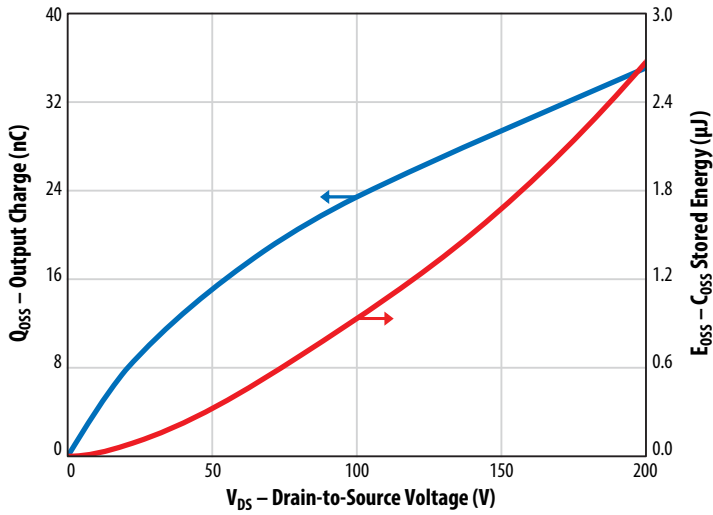


Figure 7: Typical Gate Charge

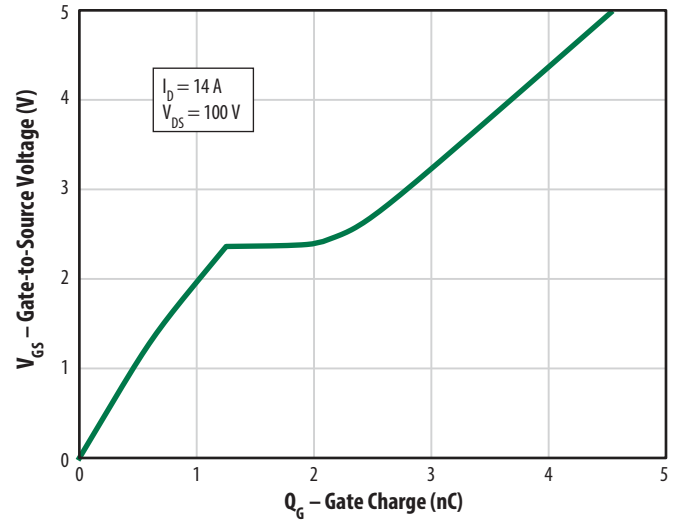


Figure 8: Typical Reverse Drain-Source Characteristics

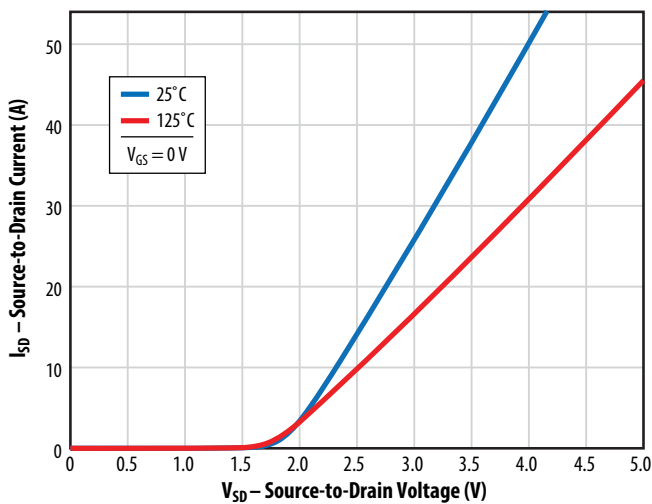
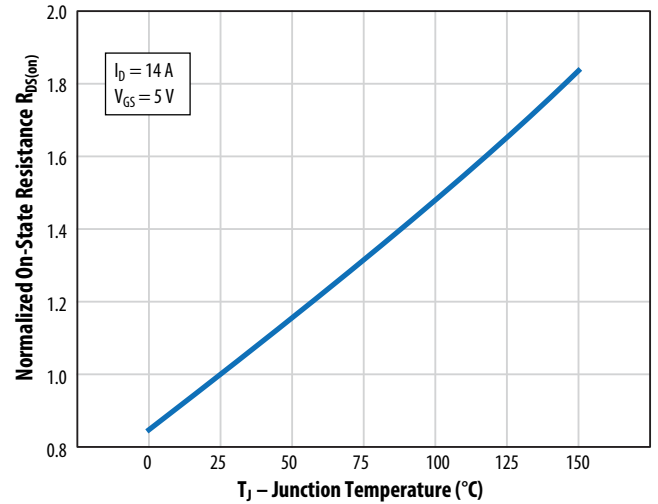


Figure 9: Typical Normalized On-State Resistance vs. Temp.



Note: Negative gate drive voltage increases the reverse drain-source voltage. EPC recommends 0 V for OFF.

Figure 10: Typical Normalized Threshold Voltage vs. Temp.

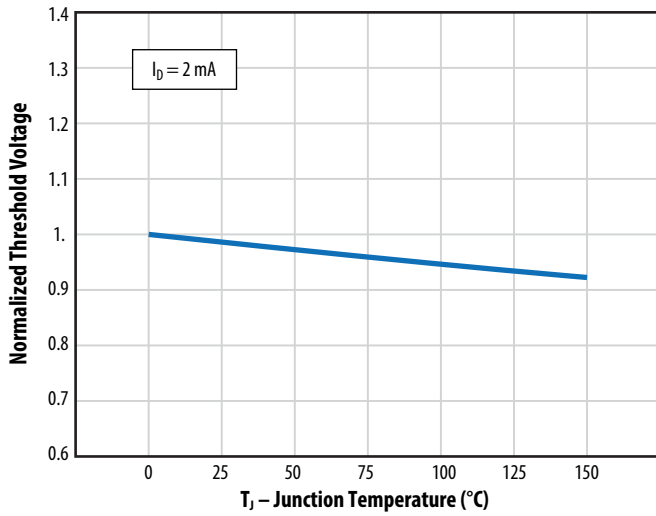


Figure 11: Safe Operating Area

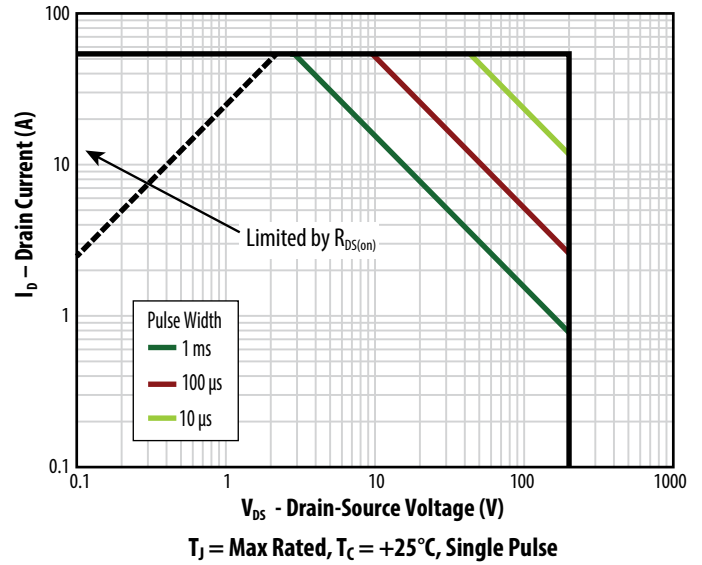
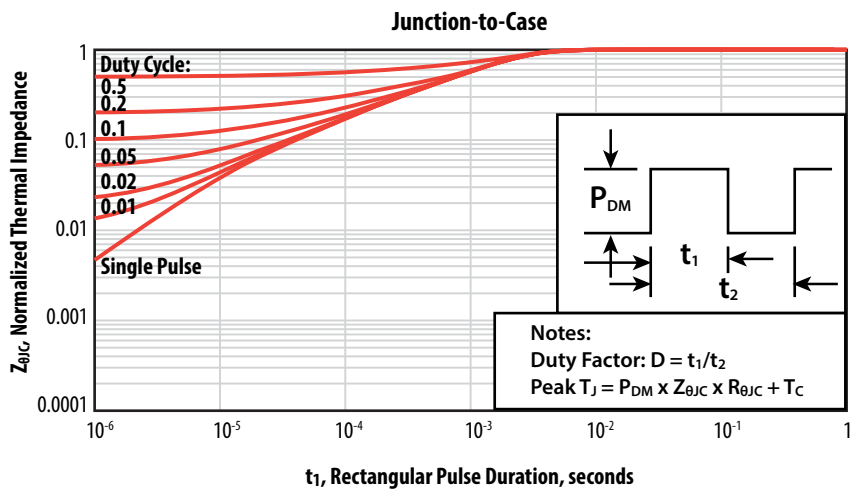
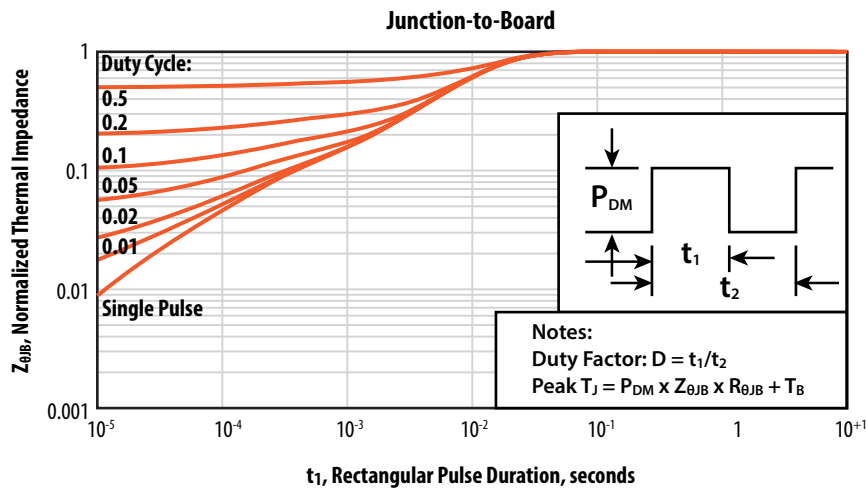
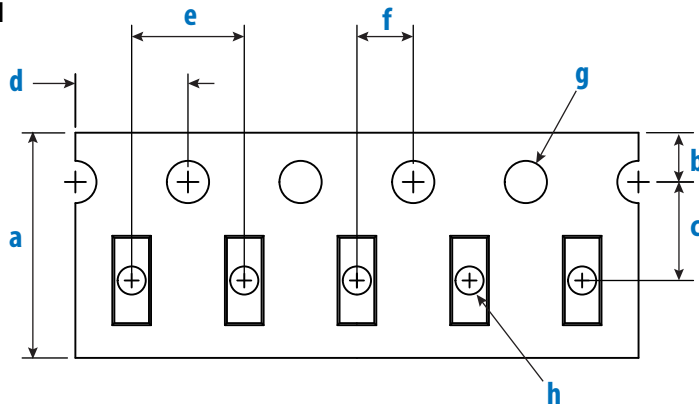
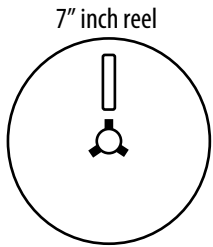


Figure 12: Typical Transient Thermal Response Curves



**TAPE AND REEL CONFIGURATION**

4 mm pitch, 8 mm wide tape on 7" reel



Loaded Tape Feed Direction →



Die orientation dot  
Gate solder bar is under this corner

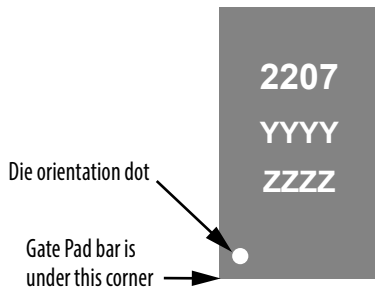
Die is placed into pocket solder bar side down (face side down)

EPC2207 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (Note 2)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60
h	1.00	1.00	1.25

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

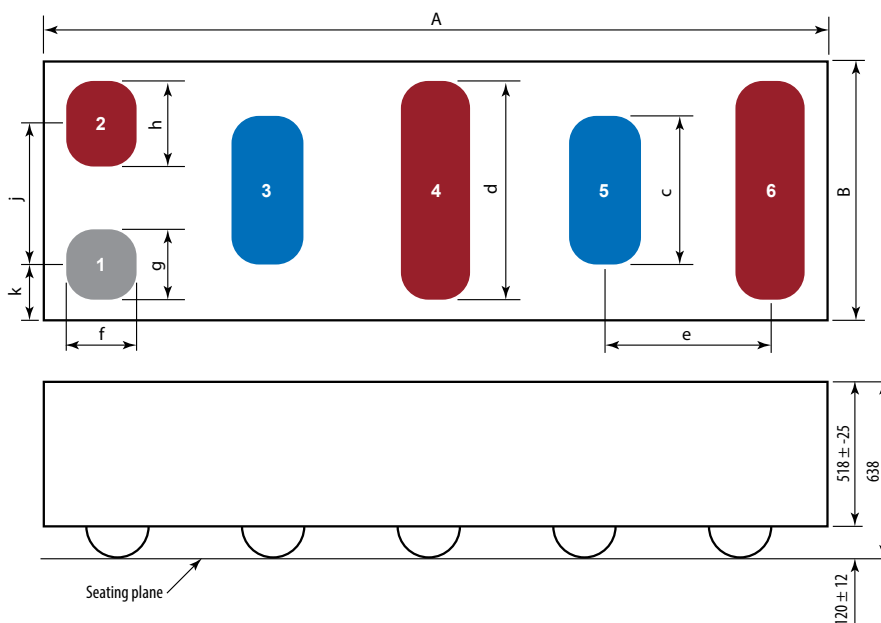
**DIE MARKINGS**



Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2207	2207	YYYY	ZZZZ

**DIE OUTLINE**

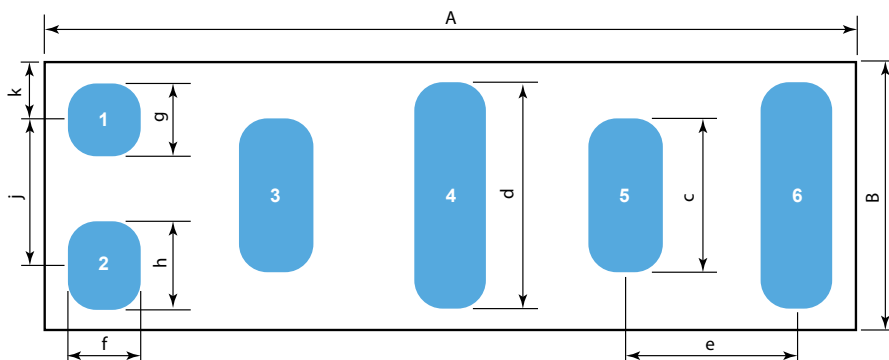
Solder Bump View



DIM	Micrometers		
	MIN	Nominal	MAX
A	2770	2800	2830
B	895	925	955
c		535	
d		775	
e		600	
f		250	
g		250	
h		300	
j		500	
k		200	

Pad 1 is Gate;  
Pads 2, 4, 6 are Source;  
Pads 3, 5 are Drain

**RECOMMENDED LAND PATTERN**  
(units in  $\mu\text{m}$ )

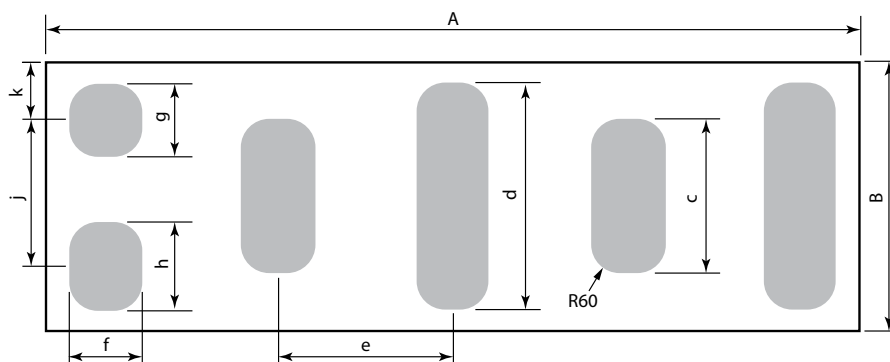


Land pattern is solder mask defined.

DIM	Nominal
A	2800
B	925
c	535
d	775
e	600
f	250
g	250
h	300
j	500
k	200

Pad 1 is Gate;  
Pads 2, 4, 6 are Source;  
Pads 3, 5 are Drain

**RECOMMENDED STENCIL DRAWING**  
(units in  $\mu\text{m}$ )



DIM	Nominal
A	2800
B	925
c	535
d	775
e	600
f	250
g	250
h	300
j	500
k	200

Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at <https://epc-co.com/epc/design-support>

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